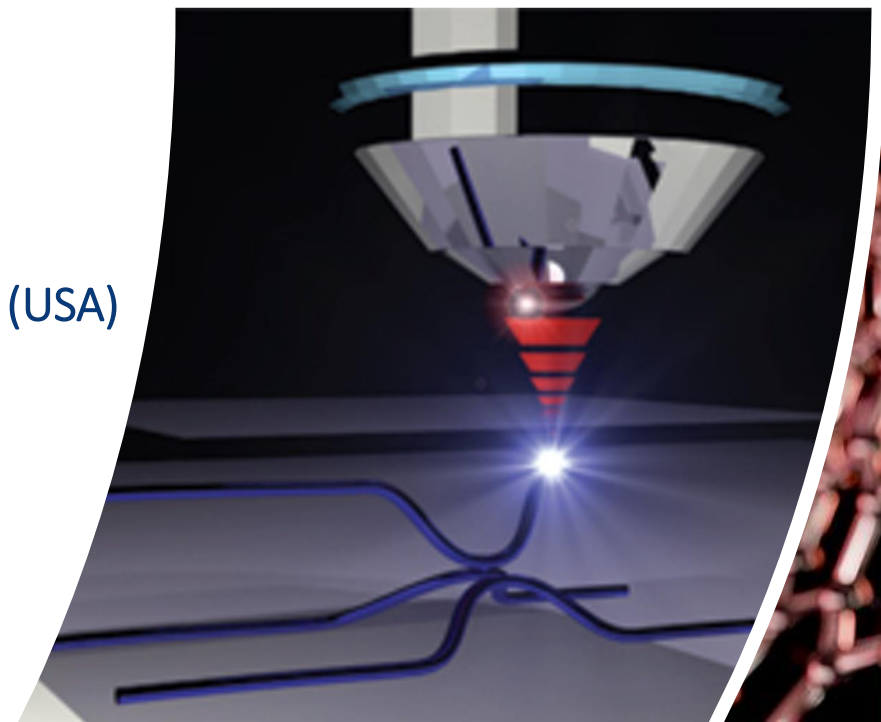
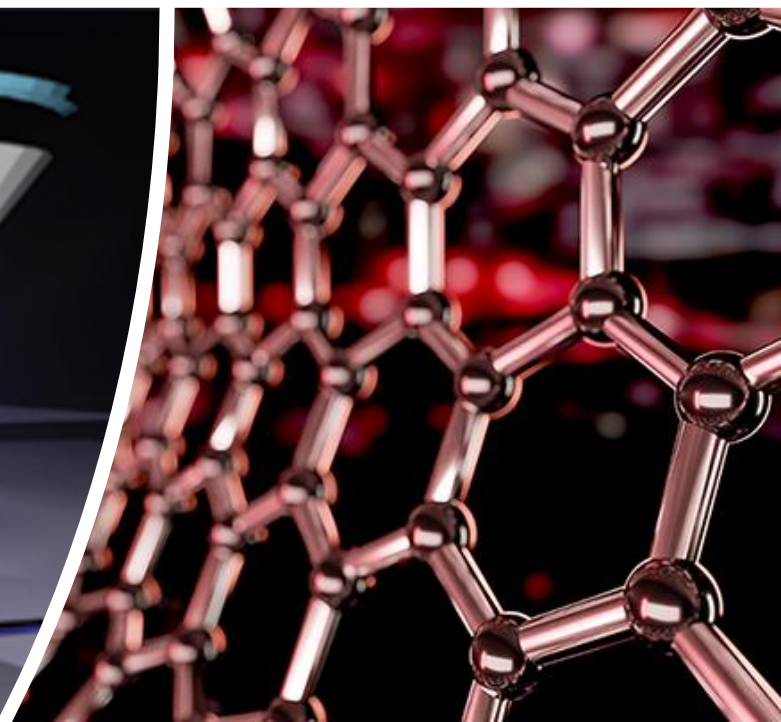
EPIC
European Photonics Industry Consortium

WAVEFRONT SENSORS
APPLIED TO
QUANTITATIVE PHASE IMAGING



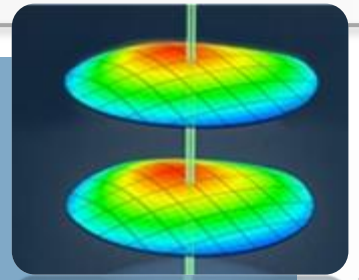
EPIC ONLINE TECHNOLOGY MEETING ON MICROSCOPY
7/13/2020

VALENTIN GENUER – BUSINESS DEVELOPER | PHASICS CORP (USA)

PHASICS
the phase control company

Phasics at a glance

PHASICS
The phase control company

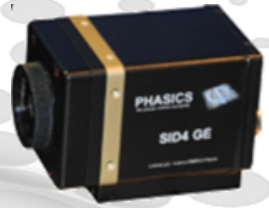


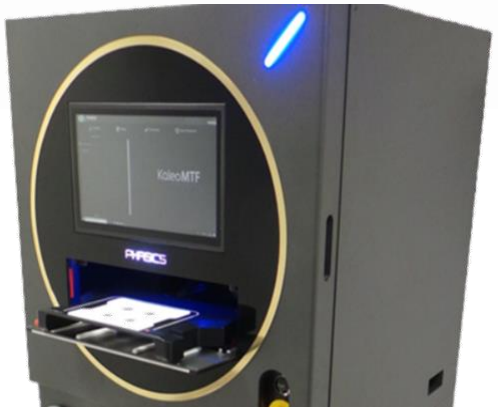
- **Core competencies**
  - Wavefront measurements
  - Wavefront sensors and test stations
- **Patented technology**
  - **Q**uadri-**W**ave **L**ateral **S**hearing **I**nterferometry
  - Spin-off from French laboratories
  - LULI (CNRS) and ONERA
- **Well established**
  - Created in 2003
  - ISO 9001 certified
  - 40 Employees

HQ south of Paris | US Branch in San Francisco CA

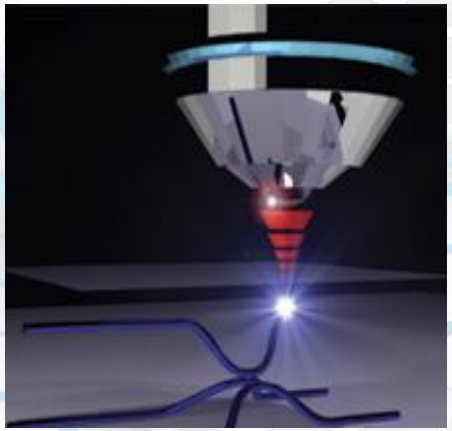
Strong distributors network

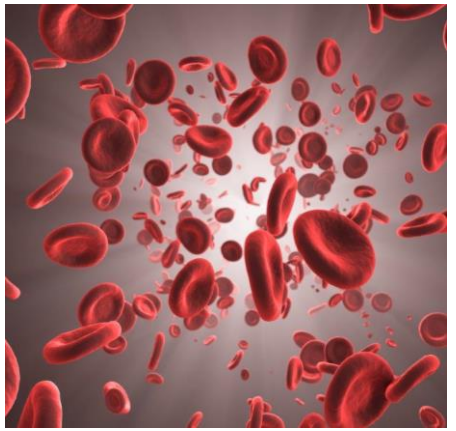
Clients worldwide
(academics & industrials)

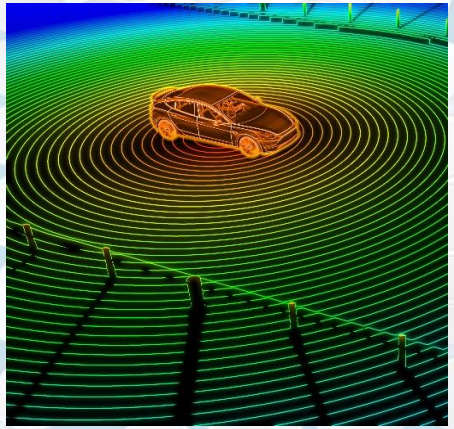


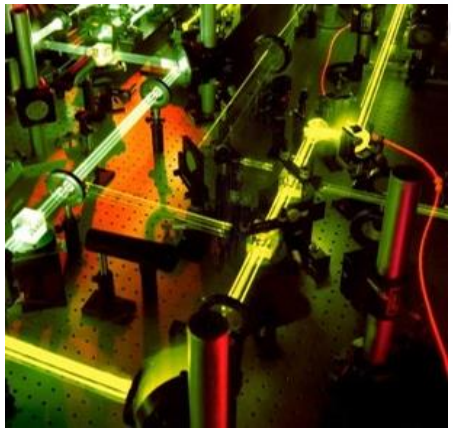


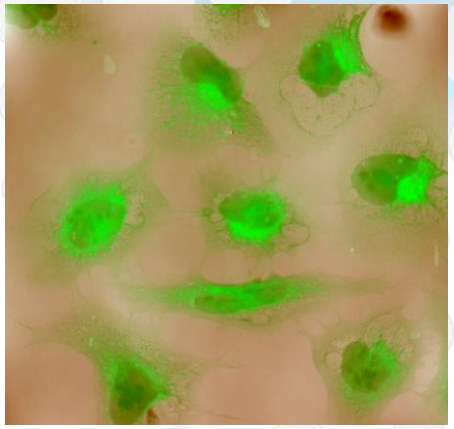
Large Range of Applications











Quantitative Phase Imaging … what for ?

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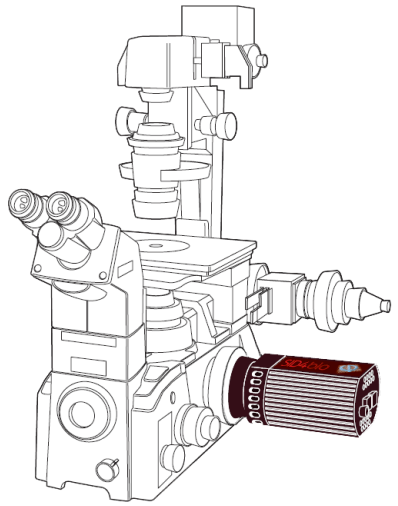
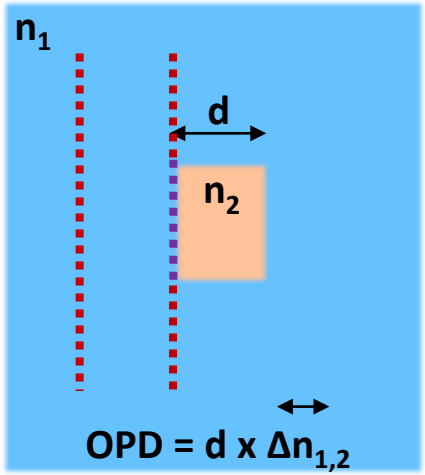
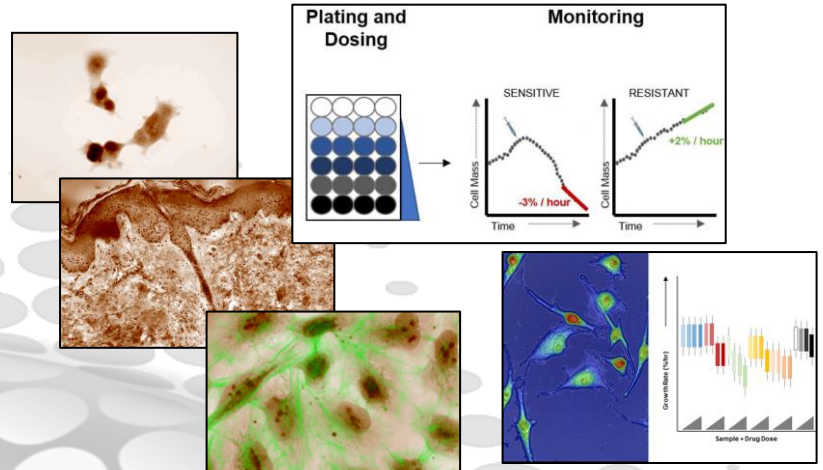


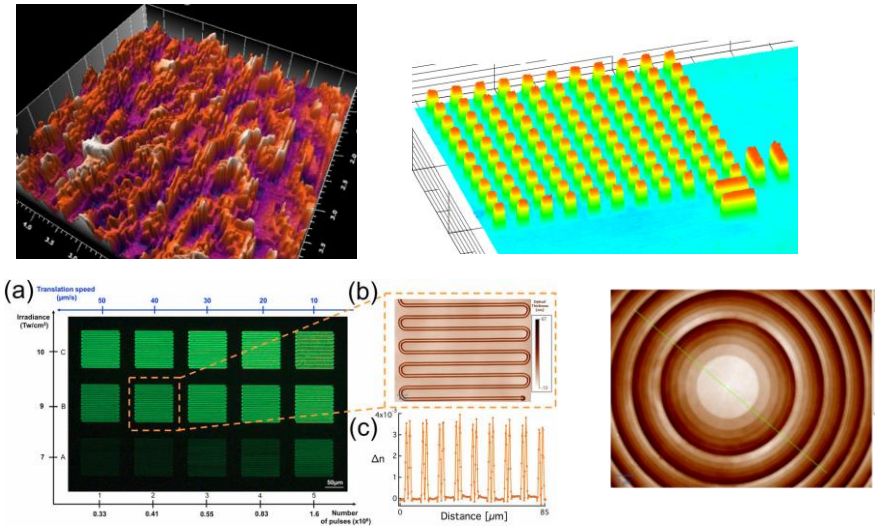


- **QPI** brings **great contrast** and **quantitative measurements**
- **QPI** with **Phasics** is:
  - ✓ **Achromatic**
  - ✓ **Not sensitive to polarization**
  - ✓ The **easiest to integrate: robust plug&play** camera for home-made setup**, OEM, production lines …**

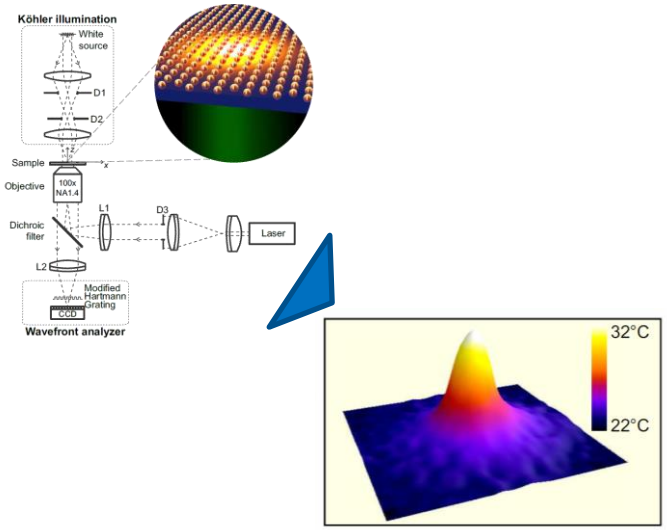
Life Science



Materials

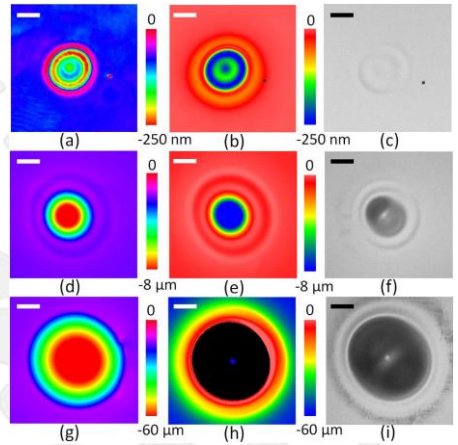


Photothermal imaging

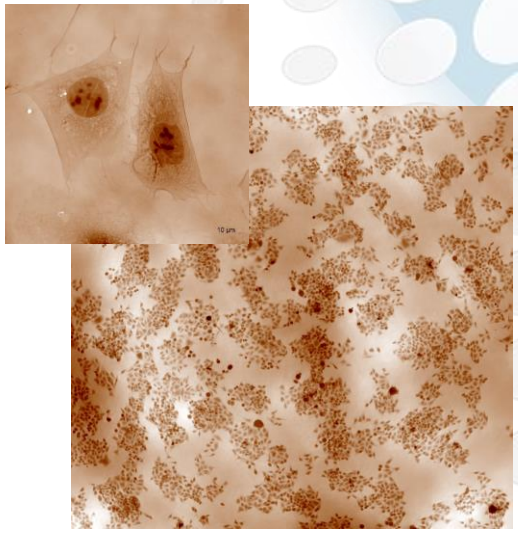


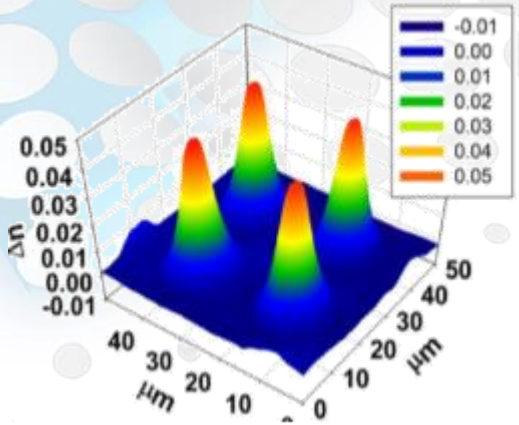
- **What can PHASICS do for EPIC's members in microscopy:**
  - **Offer the most easy to integrate QPI solution**
  - **Expertise in wavefront measurement**
  - **Help industrials releasing reliable products by solving challenging metrology problems**

- **What can EPIC's members do for PHASICS:**
  - **PHASICS has the chance to collaborate with top academic laboratories and industrial leaders working on breakthrough technologies and applications: why not with you !**
  - **Bring new ideas ! We are always eager to test new samples and see how far we can go together !**



L. Gallais *et al*
doi.org/10.1364/AO.54.008375





K. Richardson
doi.org/10.1038/s41598-018-25481-x